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(54) **METHOD AND APPARATUS FOR EXTRACTING NOISE DEFECT, AND STORAGE MEDIUM STORING INSTRUCTIONS TO PERFORM METHOD FOR EXTRACTING NOISE DEFECT**

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(57)   **ABSTRACT**

There is provided a method of extracting a noise defect from defect data. The method comprises obtaining the defect data including data on a plurality of defects, determining one of a plurality of abnormal value calculators for calculating abnormal values using each of a variety of predetermined calculation methods and calculating an abnormal value for each of the plurality of defects using one of the plurality of abnormal value calculator, generating a frequency histogram for each of the plurality of defects using the abnormal value, calculating similarity between the plurality of defects using the frequency histogram for each of the plurality of defects, and extracting the noise defect from the plurality of defects based on the similarity